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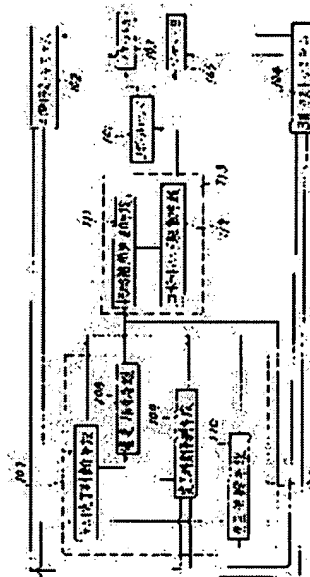
(21)Application number : 62-250358 (71)Applicant : MITSUBISHI ELECTRIC CORP
 (22)Date of filing : 02.10.1987 (72)Inventor : FURUSHIMA TAKENARI
 ISHII TADAO

(54) IC TESTING DEVICE

(57)Abstract:

PURPOSE: To shorten a test time by predicting a system which completes a test first between two test systems and holding a robot hand for inspected body supply ready on the system side.

CONSTITUTION: This device is provided with an A-side test system 102 which tests a 1st body to be inspected and a B-side test system 104 which tests a 2nd body to be inspected. A priority indicating means 108 indicates no priority, a completion period predicting means 109 computes the test completion period of both. Then an indication is sent to a microcomputer 113 which a robot hand driving means 112 and a supply position judging means 111 to hold the robot hand 101 ready in the test system which finished a test first. Thus, the waiting time in the test is utilized to perform other processes of transporting the body to be inspected and the test time can be shortened.



LEGAL STATUS

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